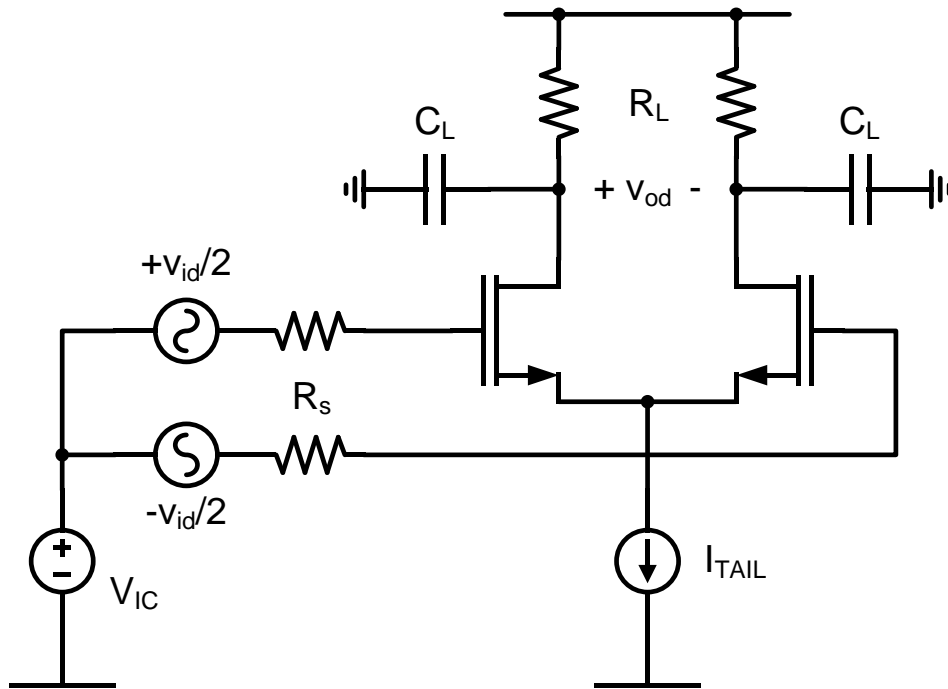


---

# Introduction to $G_m/I_D$ -based sizing

# Motivation: Basic Design Example

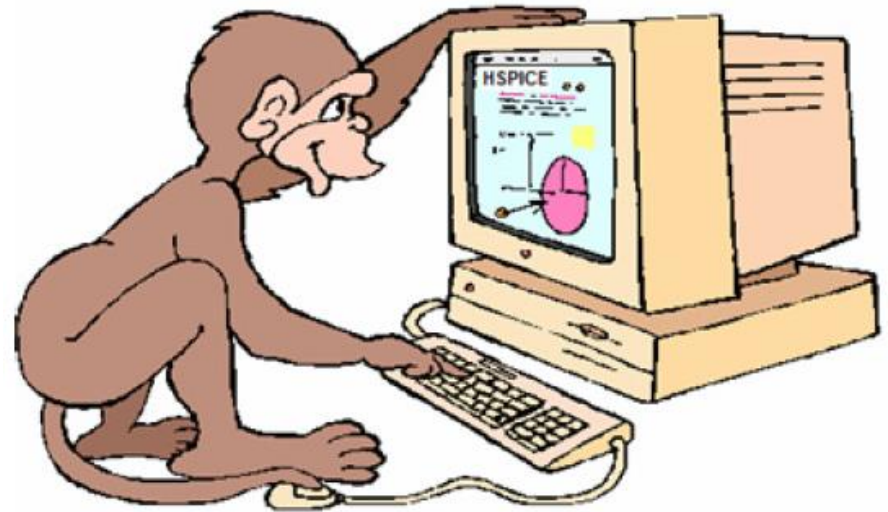


- Given specifications and objectives
  - 0.18 $\mu$ m technology
  - Low frequency gain = -4
  - $R_L=1k$ ,  $C_L=50fF$ ,  $R_s=10k\Omega$
  - Maximize bandwidth while keeping  $I_{TAIL} \leq 600\mu A$
  - Determine W/L
  - Estimate dominant and non-dominant pole

# To Be Avoided: Spice Monkeying

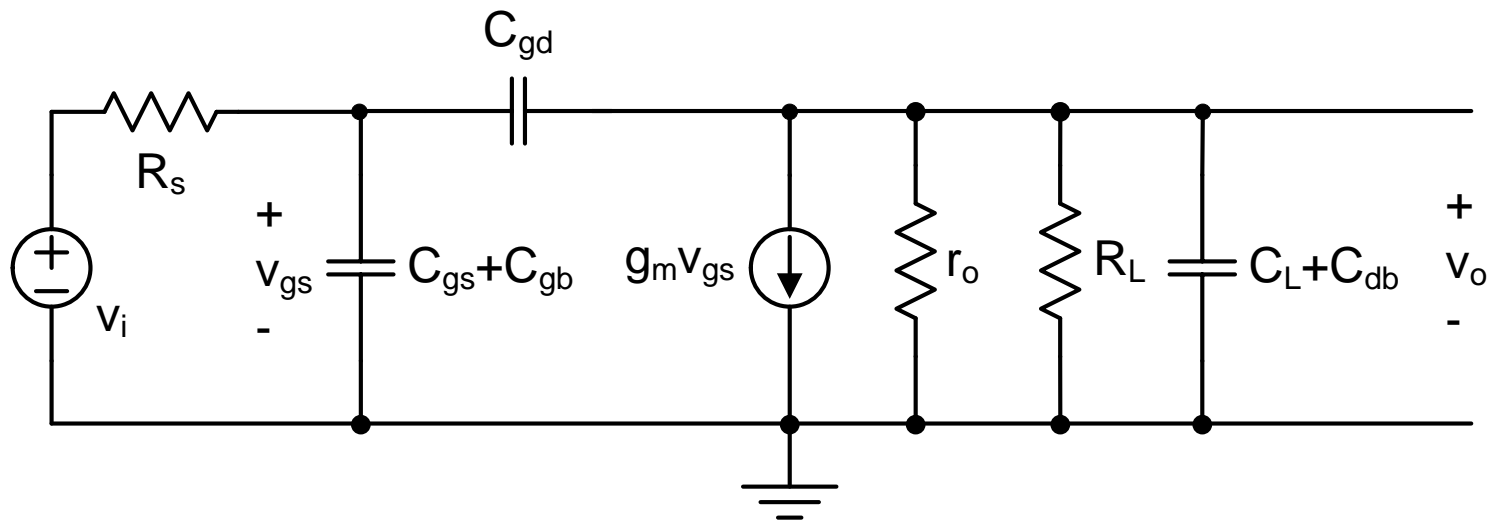
---

- One way to solve this problem is to “poke around” in Spice and play this out like a video game...
- Issues
  - Learn nothing about fundamental tradeoffs and optimality
  - Will not detect simulation or modeling errors



# Better: Systematic Design

- Start with a circuit model
- Establish links between design specs and model parameters
- Establish links between model parameters and transistor parameters
  - This is where things get problematic...



# Textbook Transistor Model

---

$$I_D = \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{GS} - V_t)^2 (1 + \lambda V_{DS})$$

$$g_m = \frac{dI_D}{dV_{GS}} = \mu C_{ox} \frac{W}{L} V_{OV} (1 + \lambda V_{DS}) = \frac{2I_D}{V_{OV}} \quad V_{OV} = V_{GS} - V_t$$

$$g_o = \frac{dI_D}{dV_{DS}} = \frac{1}{2} \mu C_{ox} \frac{W}{L} V_{OV}^2 \cdot \lambda = \frac{\lambda I_D}{1 + \lambda V_{DS}} \cong \lambda I_D$$

$$C_{gs} = \frac{2}{3} W L C_{ox} \quad \text{etc.}$$

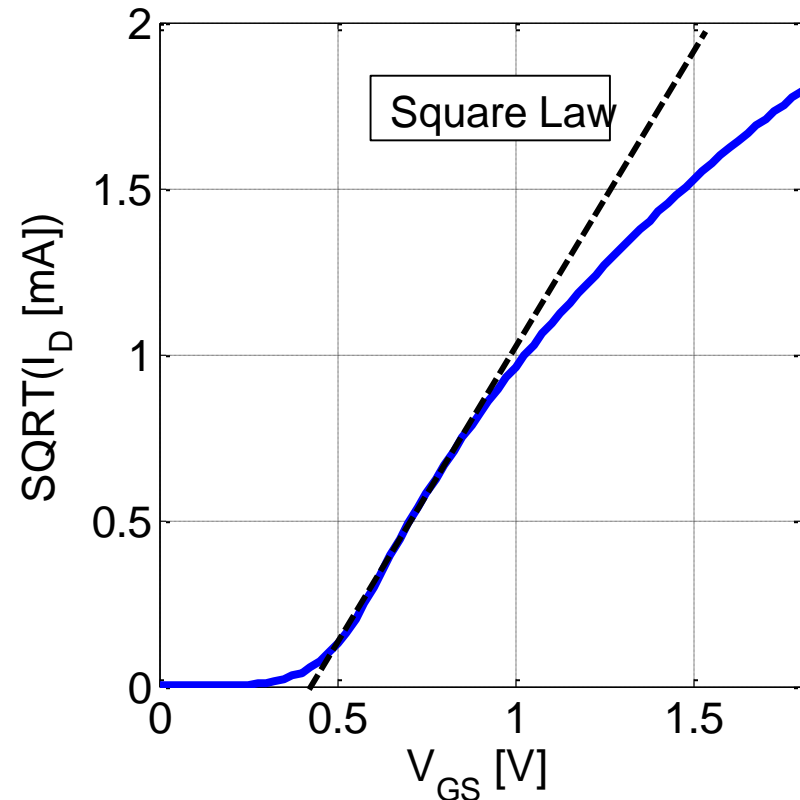
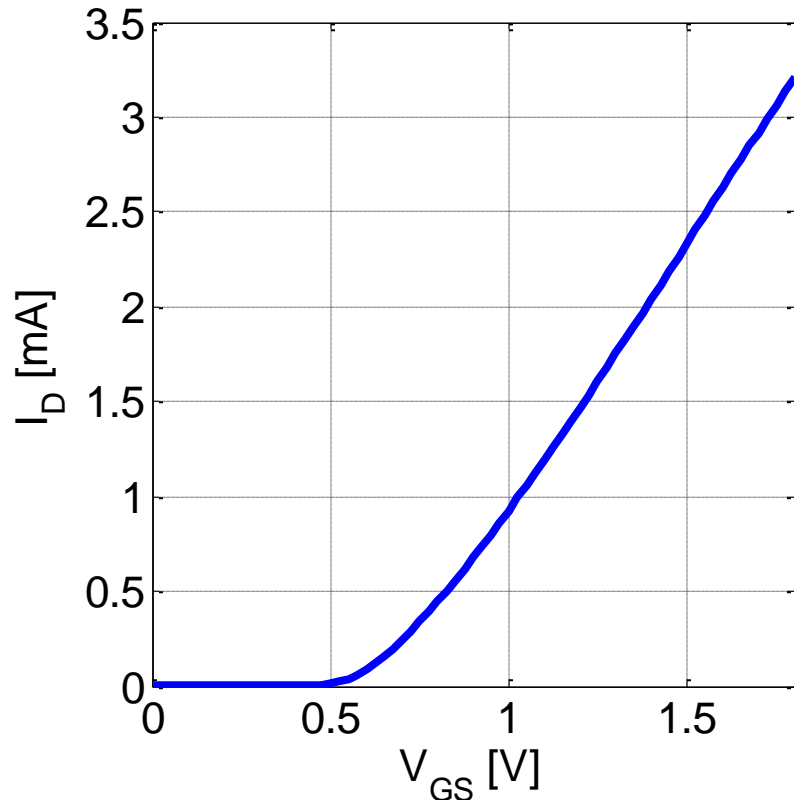
# What are $\mu C_{ox}$ (KP) and $\lambda$ (LAMBDA)?

## .MODEL nmos214 nmos

```
+acm      = 3          hdif    = 0.32e-6      LEVEL   = 49
+VERSION  = 3.1        TNOM    = 27          TOX     = 4.1E-9
+XJ       = 1E-7       NCH     = 2.3549E17    VTH0    = 0.3618397
+K1       = 0.5916053  K2     = 3.225139E-3    K3      = 1E-3
+K3B      = 2.3938862  W0     = 1E-7       NLX     = 1.776268E-7
+DVT0W    = 0          DVT1W   = 0           DVT2W   = 0
+DVT0     = 1.3127368  DVT1   = 0.3876801    DVT2    = 0.0238708
+U0       = 256.74093  UA     = -1.585658E-9    UB      = 2.528203E-18
+UC       = 5.182125E-11 VSAT   = 1.003268E5    A0      = 1.981392
+AGS      = 0.4347252  B0     = 4.989266E-7    B1      = 5E-6
+KETA     = -9.888408E-3 A1     = 6.164533E-4    A2      = 0.9388917
+RDSW     = 128.705483 PRWG   = 0.5         PRWB    = -0.2
+WR       = 1          WINT    = 0          LINT    = 1.617316E-8
+XL       = 0          XW     = -1E-8       DWG     = -5.383413E-9
+DWB      = 9.111767E-9 VOFF   = -0.0854824    NFACTOR = 2.2420572
+CIT      = 0          CDSC    = 2.4E-4       CDSCD   = 0
+CDSCB    = 0          ETA0    = 2.981159E-3    ETAB    = 9.289544E-6
+DSUB     = 0.0159753 PCLM   = 0.7245546    PDIBLC1 = 0.1568183
+PDIBLC2  = 2.543351E-3 PDIBLCB = -0.1        DROUT   = 0.7445011
+PSCBE1   = 8E10      PSCBE2  = 1.876443E-9    PVAG    = 7.200284E-3
+DELTA    = 0.01      RSH     = 6.6         MOBMOD  = 1
+PRT      = 0          UTE     = -1.5        KT1     = -0.11
+KT1L     = 0          KT2     = 0.022       UA1     = 4.31E-9
+UB1      = -7.61E-18 UC1     = -5.6E-11    AT      = 3.3E4
+W1       = 0          WLN     = 1          WW     = 0
+WWN      = 1          WWL     = 0          LL     = 0
+LLN      = 1          LW      = 0          LWN     = 1
+LWL      = 0          CAPMOD  = 2          XPART   = 1
+CGDO     = 4.91E-10  CGSO   = 4.91E-10    CGBO    = 1E-12
+CJ       = 9.652028E-4 PB      = 0.8         MJ      = 0.3836899
+CJSW     = 2.326465E-10 PBSW   = 0.8         MJSW    = 0.1253131
+CJSWG    = 3.3E-10  PBSWG  = 0.8         MJSWG   = 0.1253131
+CF       = 0          PVTH0   = -7.714081E-4    PRDSW   = -2.5827257
+PK2      = 9.619963E-4 WKETA   = -1.060423E-4    LKETA   = -5.373522E-3
+PU0      = 4.5760891 PUA     = 1.469028E-14    PUB     = 1.783193E-23
+PVSAT    = 1.19774E3 PETA0   = 9.968409E-5    PKETA   = -2.51194E-3
+nlev     = 3          kf      = 0.5e-25
```

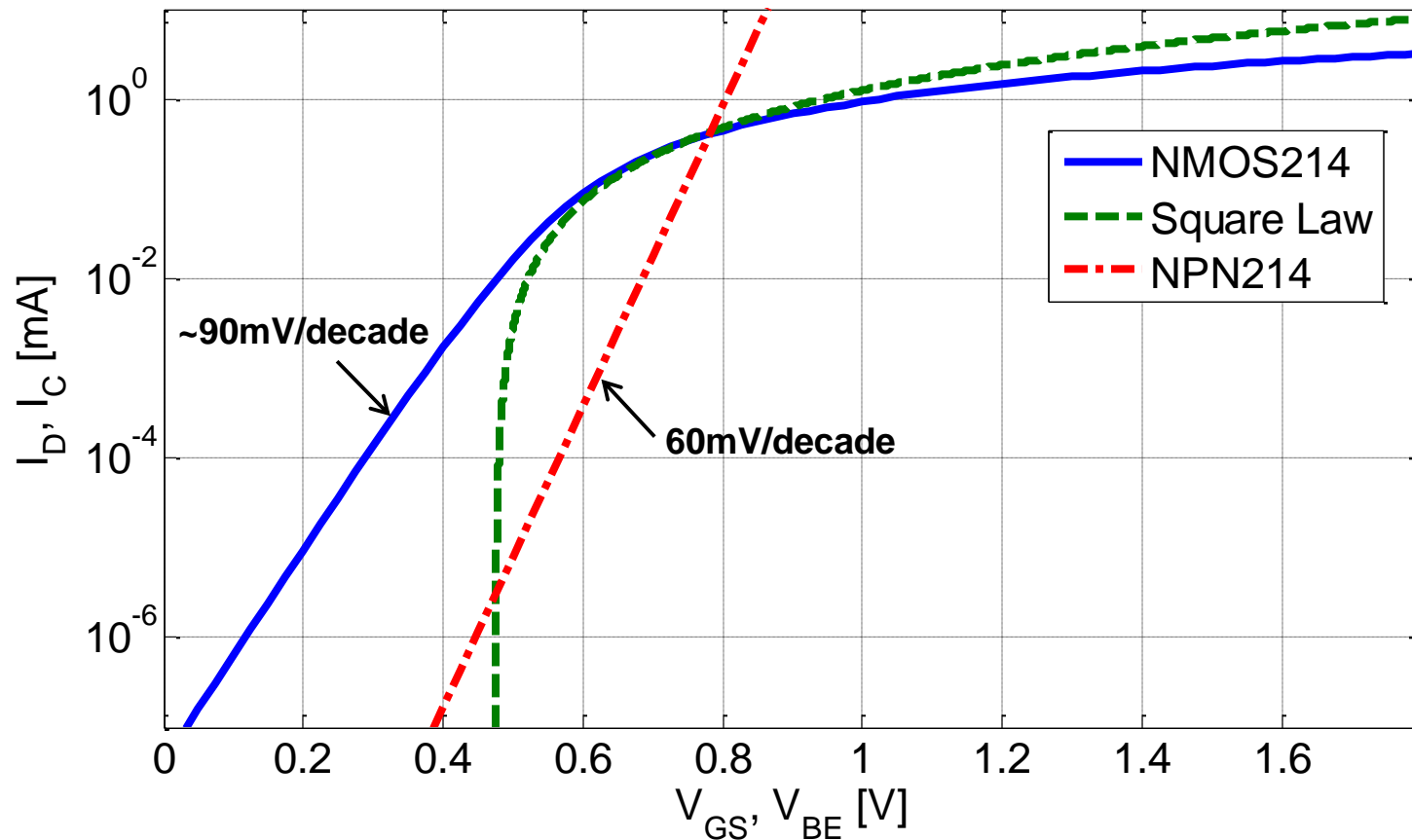
- Even for a relatively old 0.18 $\mu$ m process, the models used in simulation are quite complex
- The model card shown on the left is a 110-parameter BSIM3v3 model
  - More recent models require even more parameters (e.g. PSP, BSIM6)
  - **KP and LAMBDA are nowhere to be found**
- It turns out that the I-V characteristics of a modern MOSFET cannot be accurately described by the square law

# Simulation (NMOS, 5/0.18 $\mu\text{m}$ , $V_{DS}=1.8\text{V}$ )



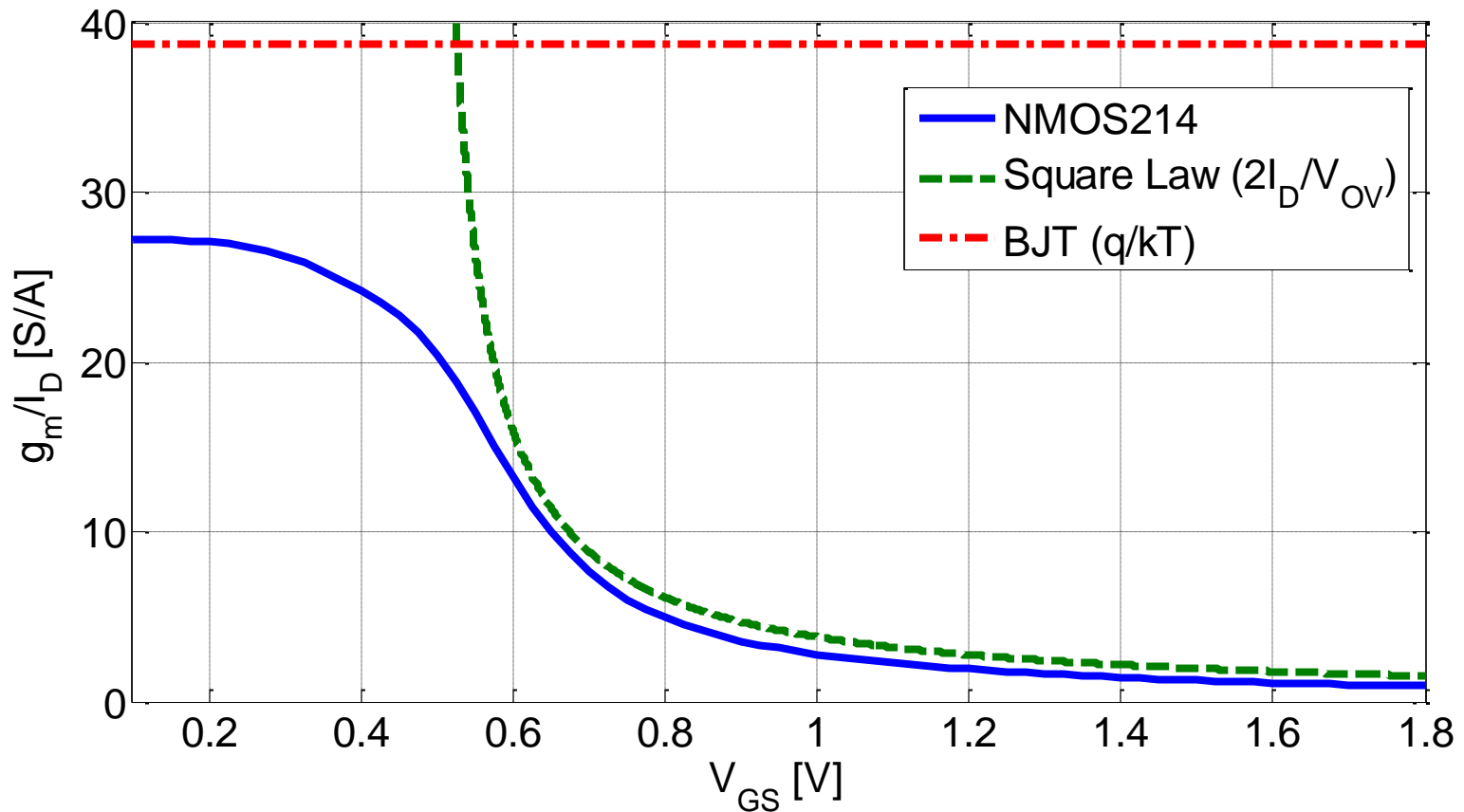
- Two observations
  - The transistor does not abruptly turn off at some  $V_t$
  - The current is not perfectly quadratic in  $(V_{GS}-V_t)$

# Current on a Log Scale



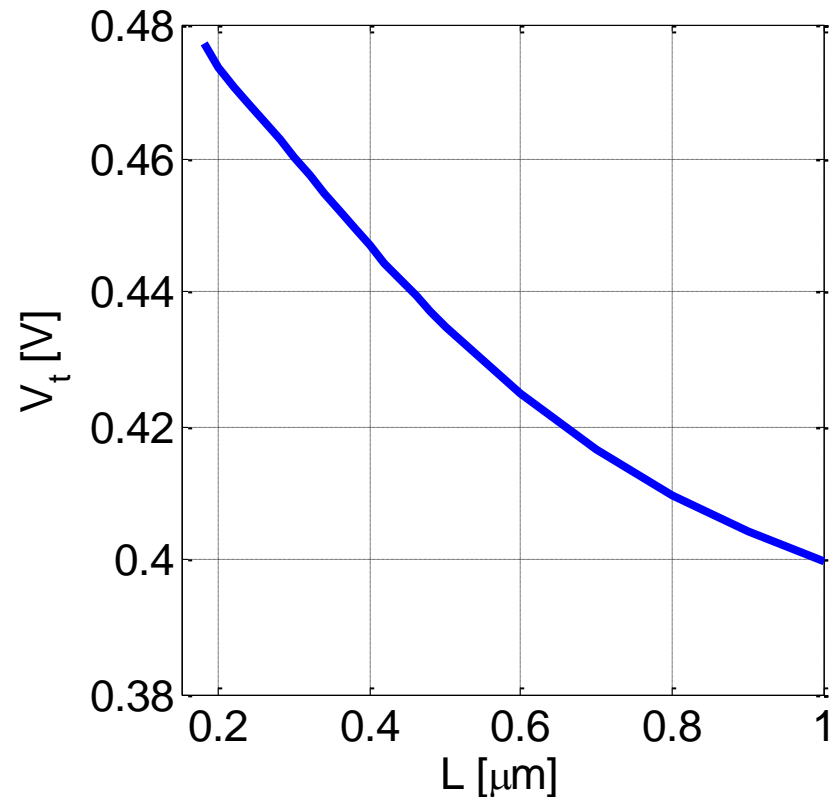
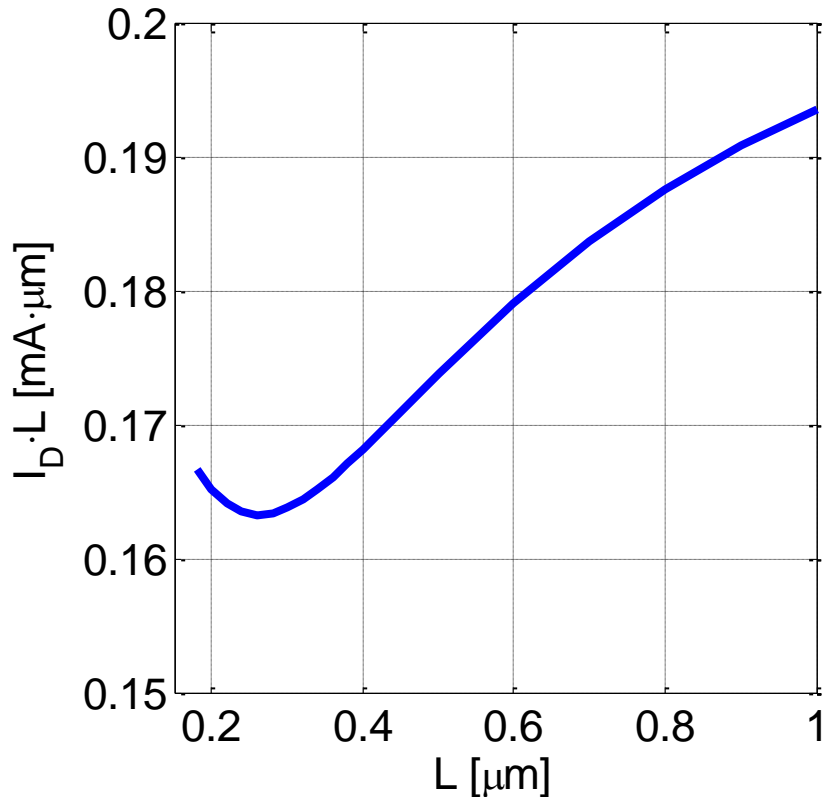


$$g_m/I_D$$



- The square law fails miserably at predicting  $g_m/I_D$  for low  $V_{GS}$

# Length Scaling and $V_t$



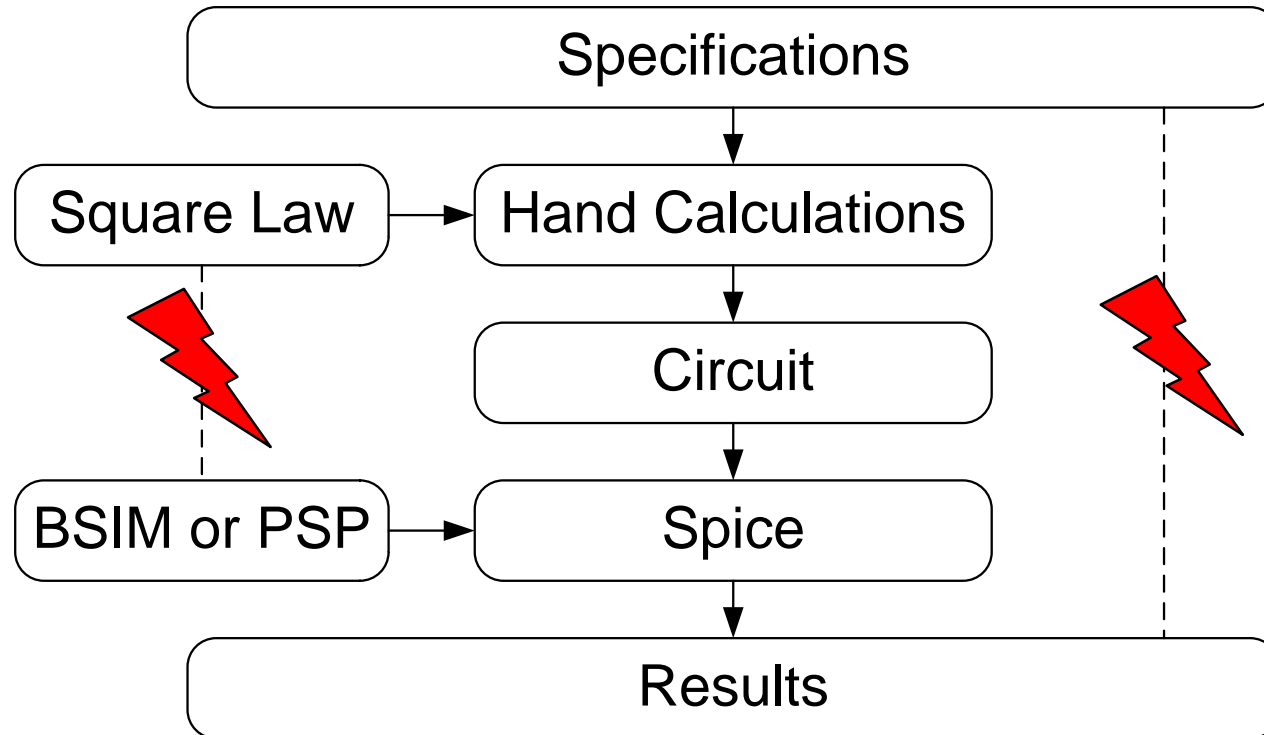
- The current does not scale perfectly with  $1/L$  ( $I_D \cdot L \neq \text{const.}$ )
- The threshold voltage of the device depends on the channel length

# Cause of these Complications

---

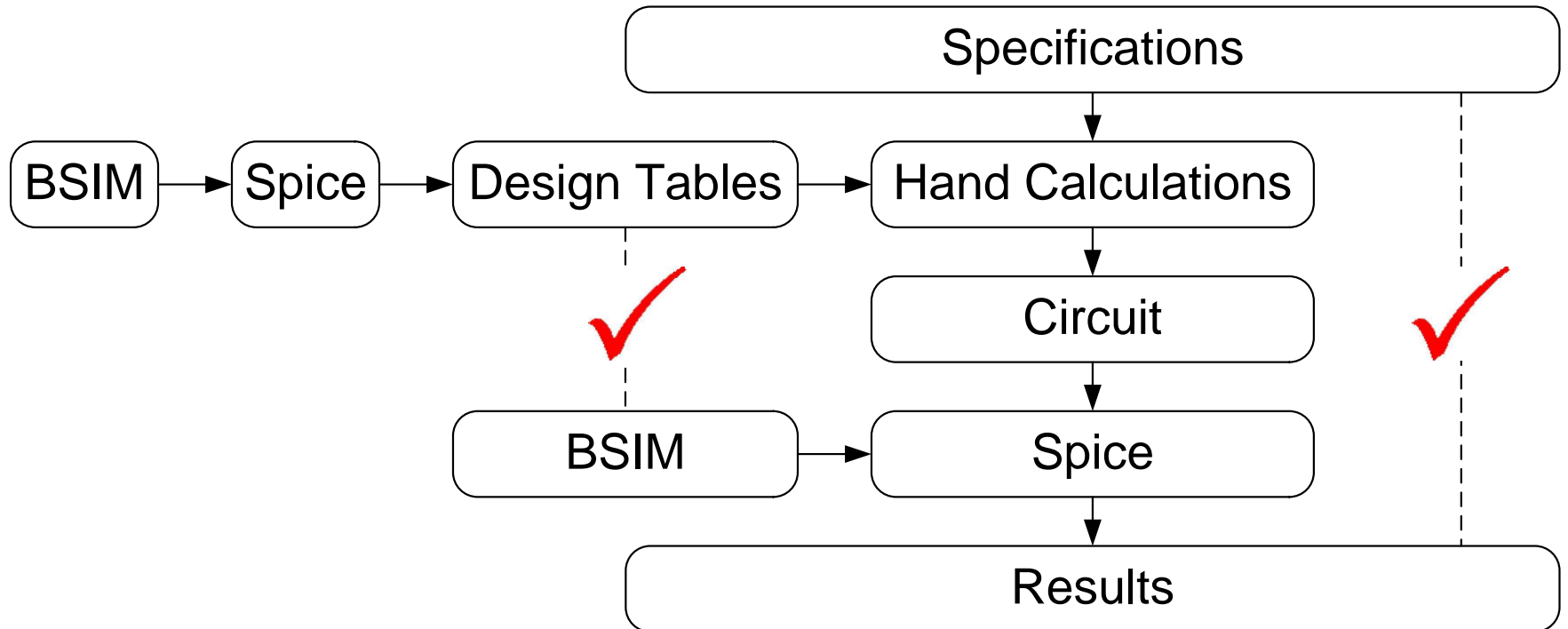
- Weak inversion
  - For  $V_{GS}$  below of near  $V_t$ , the current is caused by diffusion instead of drift; MOSFET behaves similar to BJT
- Moderate inversion
  - A wild mix of drift and diffusion currents
- Strong inversion
  - Mostly drift current, but short channel effects complicate the transistor behavior
    - Velocity saturation due to high lateral field
    - Mobility degradation due to high vertical field
- In addition, there are several effects related to small geometries
  - Strong  $V_{DS}$  dependence of  $I_D$ ,  $r_o$  and  $V_t$  (DIBL)
  - $V_t$  depends on channel length (SCE and RSCE)

# The Problem



- Since there is a disconnect between actual transistor behavior and the simple square law model, any square-law driven design optimization will be far off from Spice results

# The Solution



- Use pre-computed spice data in hand calculations

# Starting Point: Technology Characterization via DC Sweep

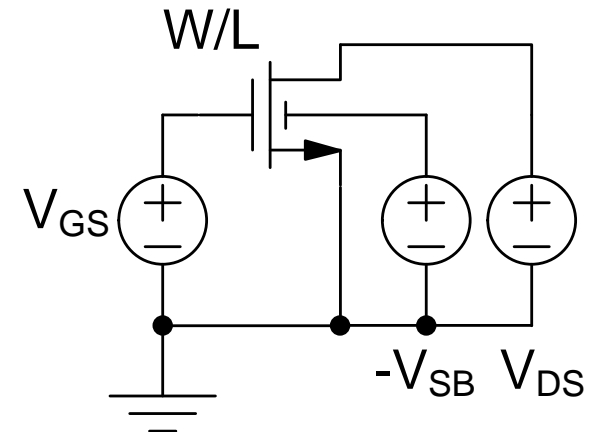
```
* /usr/class/ee214b/hspice/techchar.sp

.inc '/usr/class/ee214b/hspice/ee214_hspice.sp'
.inc 'techchar_params.sp'
.param ds = 0.9
.param gs = 0.9

vdsn      vdn 0          dc 'ds'
vgasn     vgn 0          dc 'gs'
vbsn      vbn 0          dc '-subvol'
mn        vdn vgn 0 vbn nmos214 L='length' W='width'

.options dccap post brief accurate nomod
.dc gs 0 'gsmax' 'gsstep' ds 0 'dsmax' 'dsstep'

.probe n_id    = par('i(mn)')
.probe n_vt    = par('vth(mn)')
.probe n_gm    = par('gmo(mn)')
.probe n_gmb   = par('gmbso(mn)')
.probe n_gds   = par('gdso(mn)')
.probe n_cgg   = par('cggbo(mn)')
.probe n_cgs   = par('-cgsbo(mn)')
.probe n_cgd   = par('-cgdbo(mn)')
.probe n_cgb   = par('cbgbo(mn)')
.probe n_cdd   = par('cddbo(mn)')
.probe n_css   = par('-cbsbo(mn)-cgsbo(mn)')
```



# Store Data in a Matlab Structure

```
>> load 180n.mat;

>> nch

nch =
    ID: [4-D double]
    VT: [4-D double]
    GM: [4-D double]
    GMB: [4-D double]
    GDS: [4-D double]
    CGG: [4-D double]
    CGS: [4-D double]
    CGD: [4-D double]
    CGB: [4-D double]
    CDD: [4-D double]
    CSS: [4-D double]
    VGS: [73x1 double]
    VDS: [73x1 double]
    VSB: [11x1 double]
     L: [22x1 double]
     W: 5

>> size(nch.ID)

ans =
    22    73    73    11
```

Four-dimensional arrays

$$I_D(L, V_{GS}, V_{DS}, V_{SB})$$

$$V_t(L, V_{GS}, V_{DS}, V_{SB})$$

$$g_m(L, V_{GS}, V_{DS}, V_{SB})$$

...

# Lookup Function (For Convenience)

---

```
>> lookup(nch, 'ID', 'VGS', 0.5, 'VDS', 0.5)
```

```
ans = 8.4181e-006
```

```
>> help lookup
```

The function "lookup" extracts a desired subset from the 4-dimensional simulation data. The function interpolates when the requested points lie off the simulation grid.

There are three basic usage modes:

- (1) Simple lookup of parameters at given (L, VGS, VDS, VSB)
- (2) Lookup of arbitrary ratios of parameters, e.g. GM\_ID, GM\_CGG at given (L, VGS, VDS, VSB)
- (3) Cross-lookup of one ratio against another, e.g. GM\_CGG for some GM\_ID

In usage scenarios (1) and (2) the input parameters (L, VGS, VDS, VSB) can be listed in any order and default to the following values when not specified:

```
L = min(data.L); (minimum length used in simulation)
VGS = data.VGS; (VGS vector used during simulation)
VDS = max(data.VDS)/2; (VDD/2)
VSB = 0;
```



# Key Question

---

- How can we use all this data for systematic design?
- Many options exist
  - And you can invent your own, if you like
- Method that I promote
  - Look at the transistor in terms of width-independent figures of merit that are intimately linked to design specification
    - Rather than some physical modeling parameters that do not directly relate to circuit specs)
  - Think about the design tradeoffs in terms of the MOSFET's inversion level, using  $g_m/I_D$  as a proxy

# Figures of Merit for Design

---

## Square Law

- Transconductance efficiency
  - Want large  $g_m$ , for as little current as possible

$$\frac{g_m}{I_D}$$

$$= \frac{2}{V_{OV}}$$

- Transit frequency
  - Want large  $g_m$ , without large  $C_{gg}$

$$\frac{g_m}{C_{gg}}$$

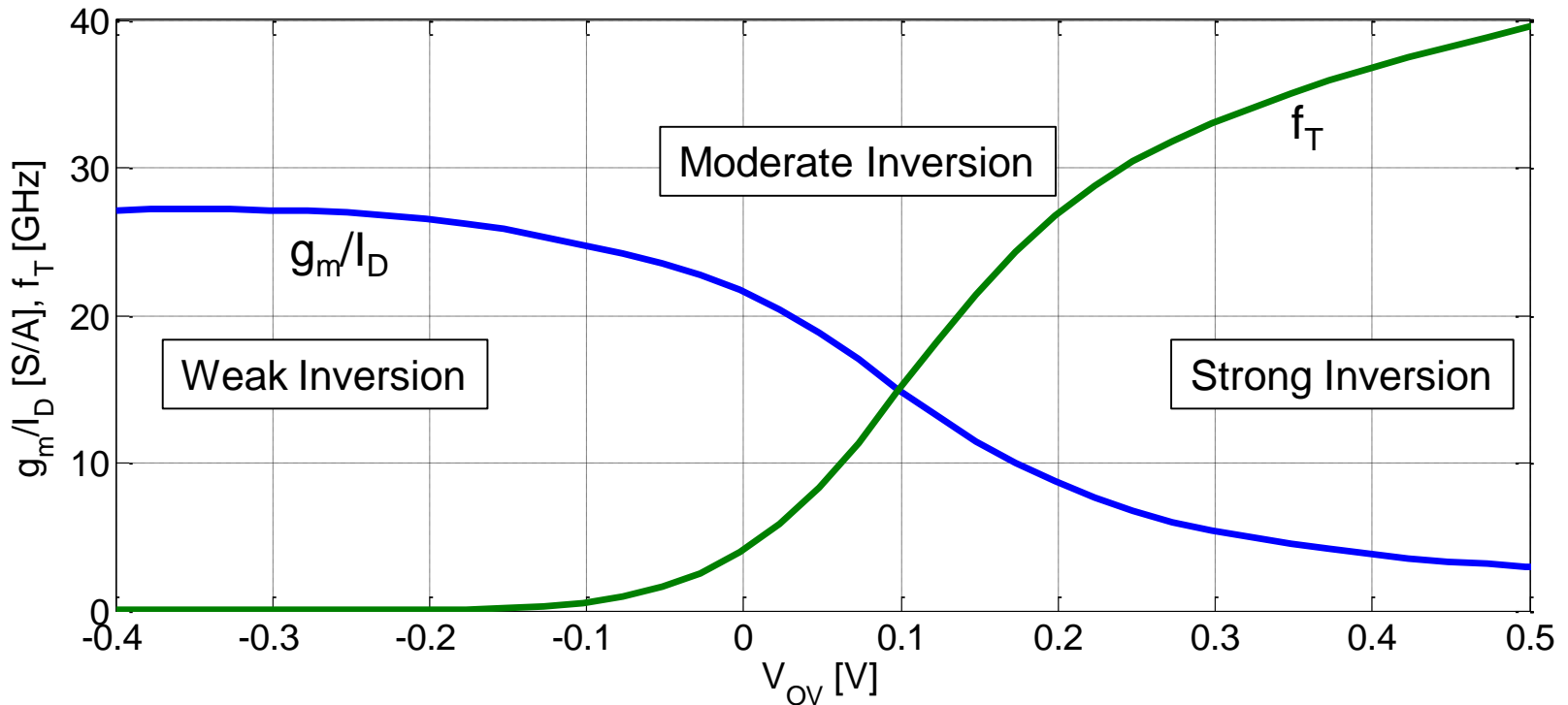
$$\approx \frac{3}{2} \frac{\mu V_{OV}}{L^2}$$

- Intrinsic gain
  - Want large  $g_m$ , but no  $g_o$

$$\frac{g_m}{g_o}$$

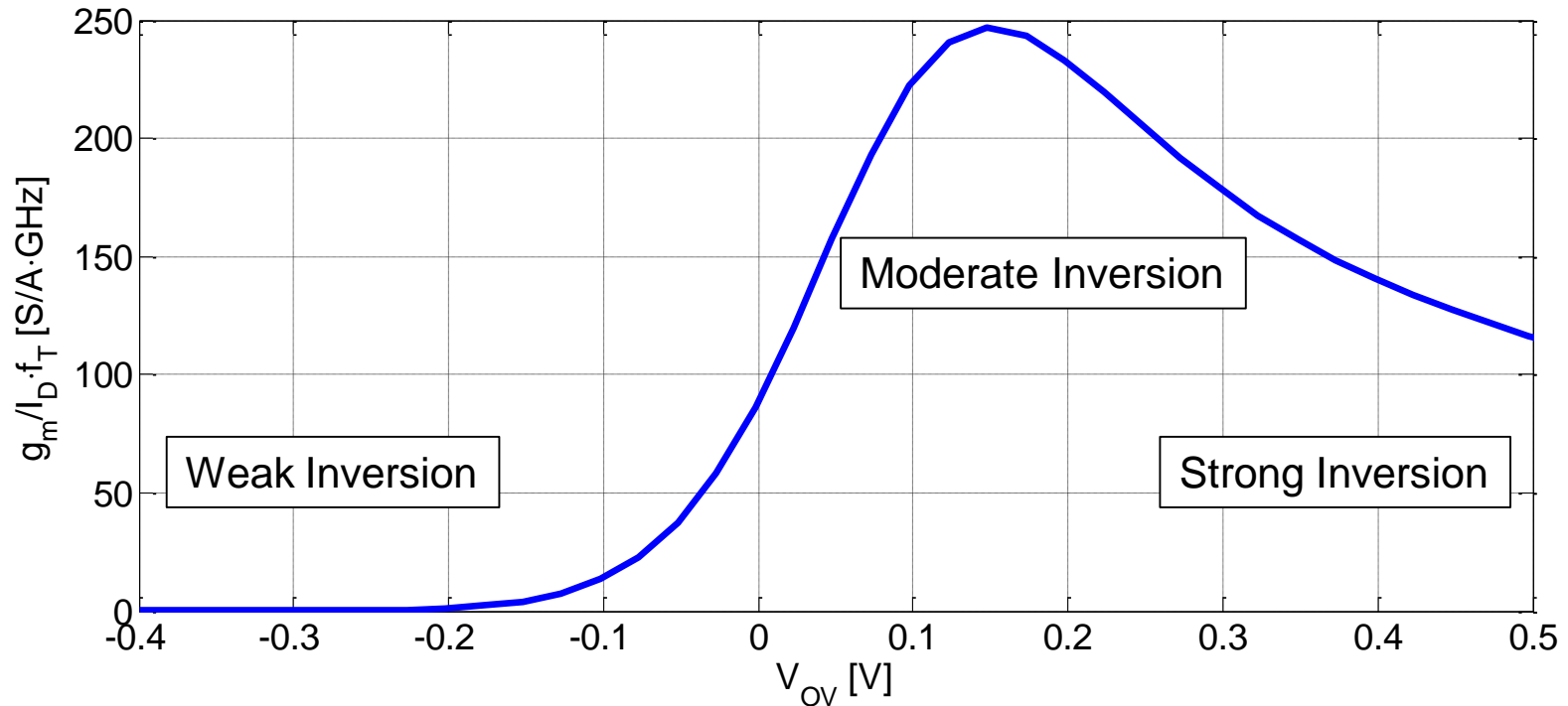
$$\approx \frac{2}{\lambda V_{OV}}$$

# Design Tradeoff: $g_m/I_D$ and $f_T$



- Weak inversion: Large  $g_m/I_D$  ( $>20$  S/A), but small  $f_T$
- Strong inversion: Small  $g_m/I_D$  ( $<10$  S/A), but large  $f_T$

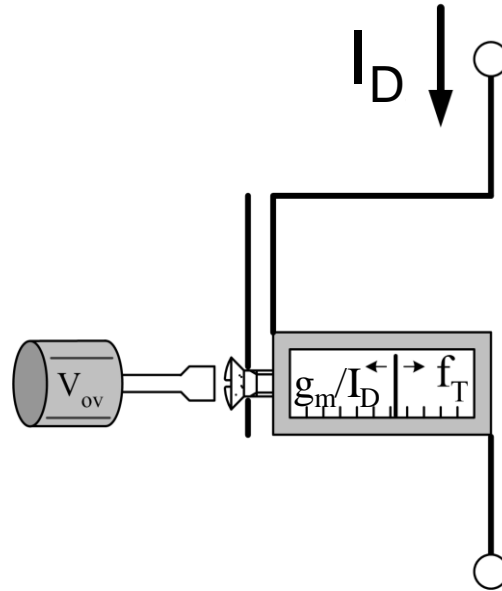
# Product of $g_m/I_D$ and $f_T$



- Interestingly, the product of  $g_m/I_D$  and  $f_T$  peaks in moderate inversion
- Operating the transistor in moderate inversion is optimal when we value speed and power efficiency equally (not always the case)

# Design in a Nutshell

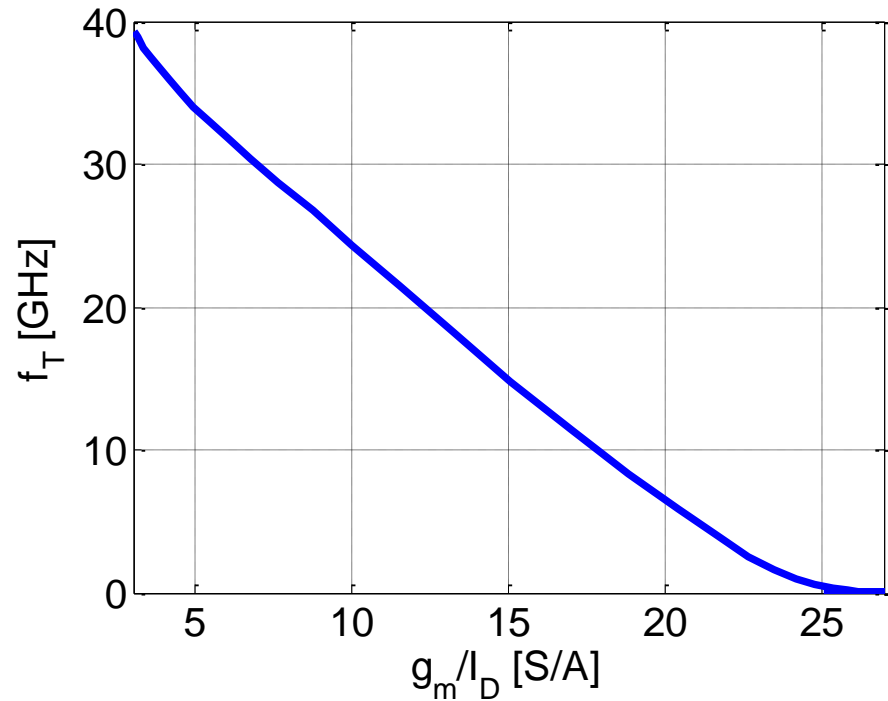
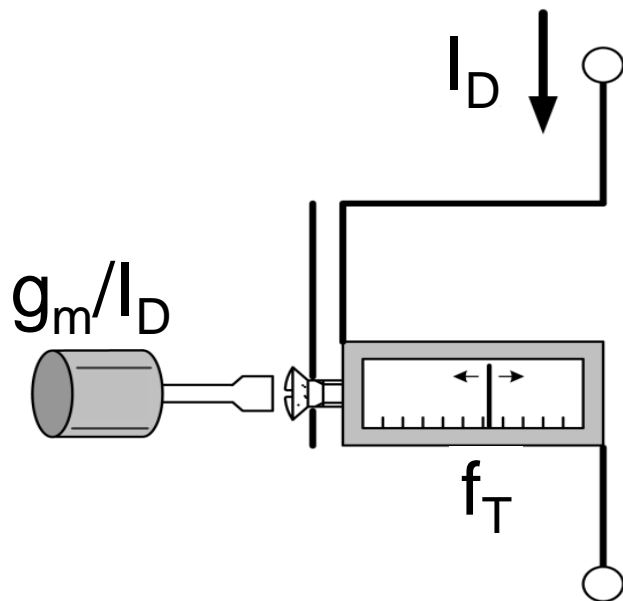
---



- Choose the inversion level according to the proper tradeoff between speed ( $f_T$ ) and efficiency ( $g_m/I_D$ ) for the given circuit
- The inversion level is fully determined by the gate overdrive  $V_{OV}$ 
  - But,  $V_{OV}$  is not a very interesting parameter outside the square law framework; not much can be computed from  $V_{OV}$

# Eliminating $V_{OV}$

- The inversion level is also fully defined once we pick  $g_m/I_D$ , so there is no need to know  $V_{OV}$ 
  - Even  $V_{Dsat}$  can be estimated using  $2 / (g_m/I_D)$



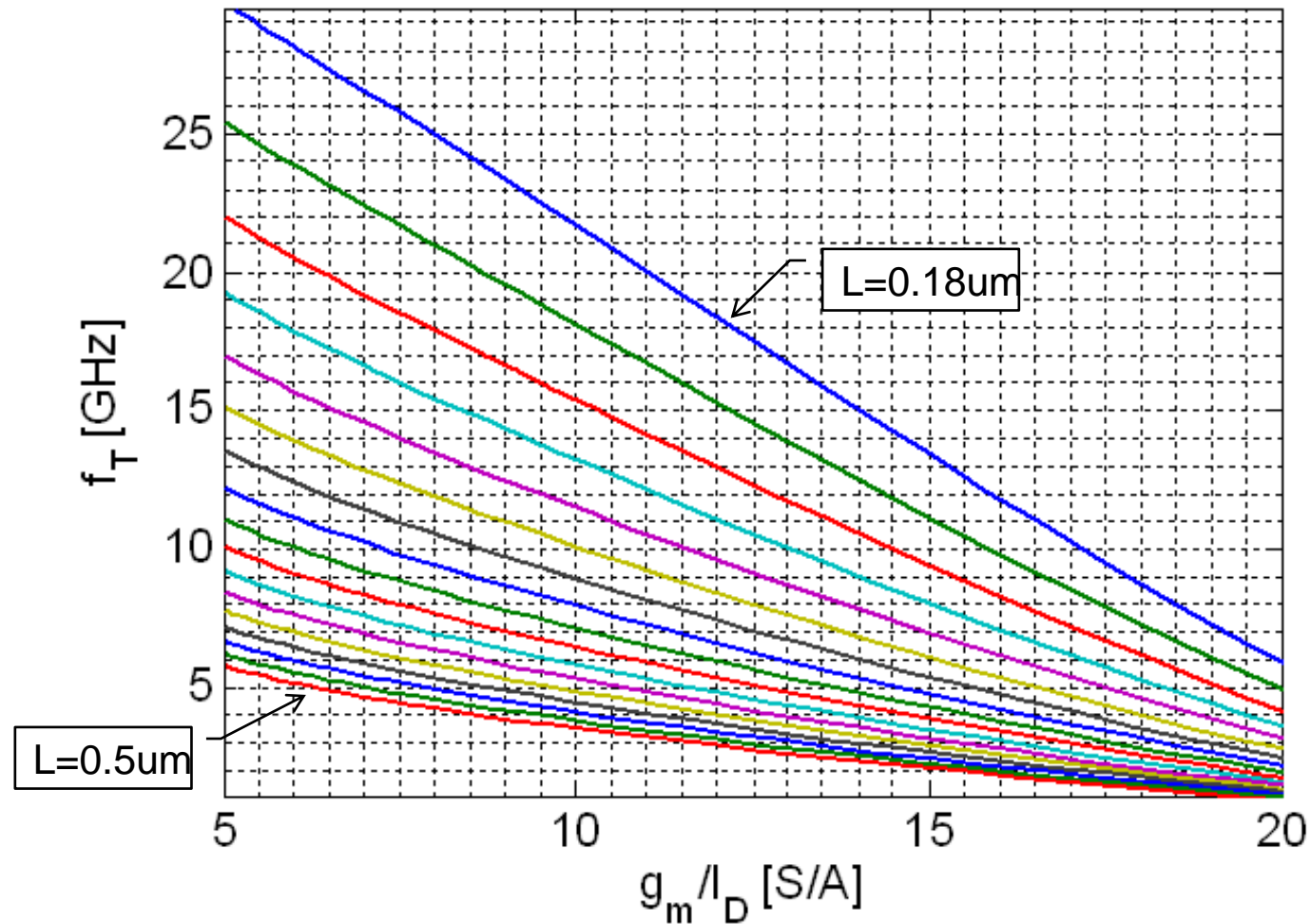
# $g_m/I_D$ -centric Technology Characterization

---

- Plot the following parameters for a reasonable range of  $g_m/I_D$  and channel lengths
  - Transit frequency ( $f_T$ )
  - Intrinsic gain ( $g_m/g_o$ )
- Also plot relative estimates of extrinsic capacitances
  - $C_{gd}/C_{gg}$  and  $C_{dd}/C_{gg}$
- Note that all of these parameters are (to first order) independent of device width
- In order to compute device widths, we need one more plot that links  $g_m/I_D$  and current density  $I_D/W$

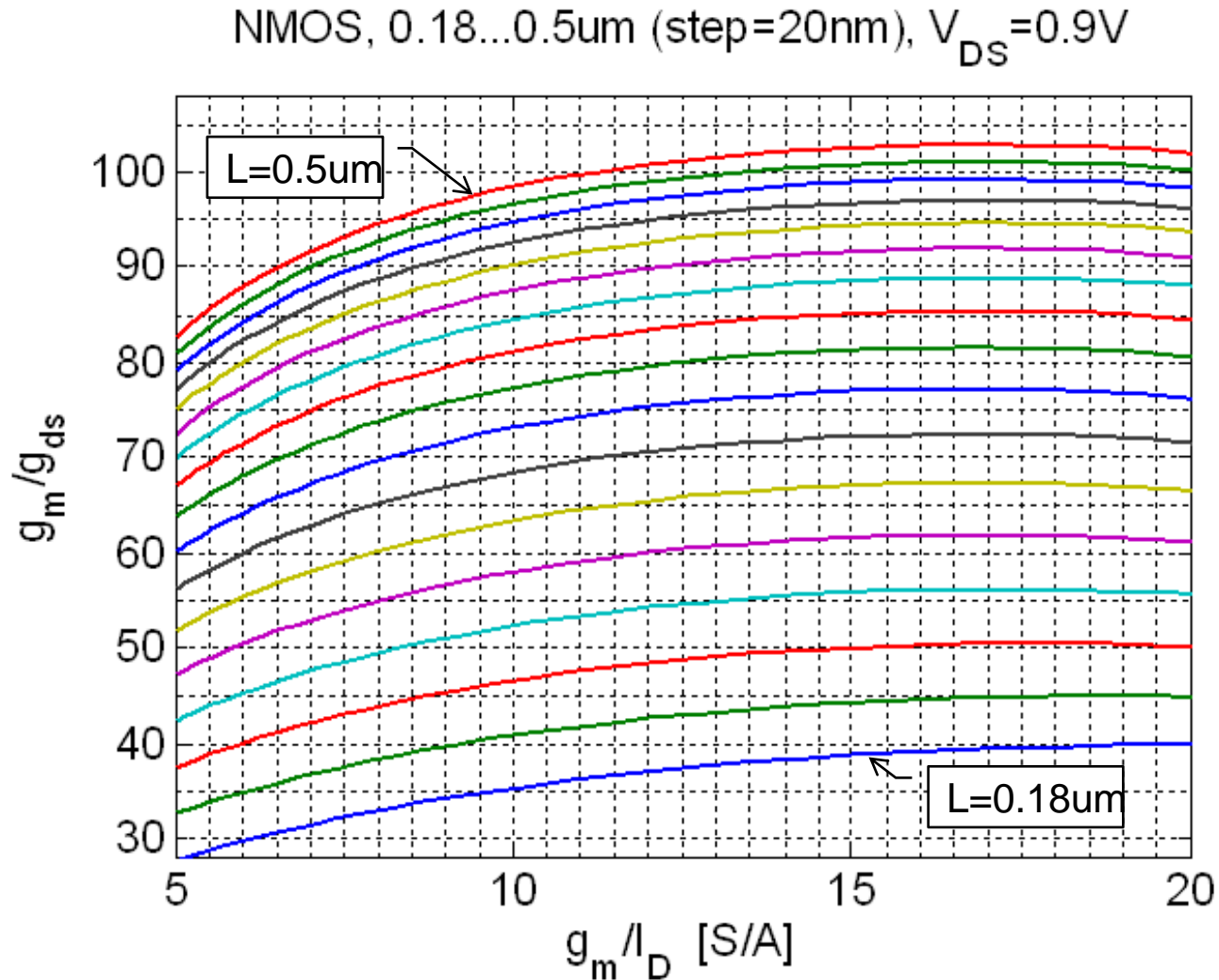
# Transit Frequency Chart

NMOS, 0.18...0.5 $\mu$ m (step=20nm),  $V_{DS}=0.9V$



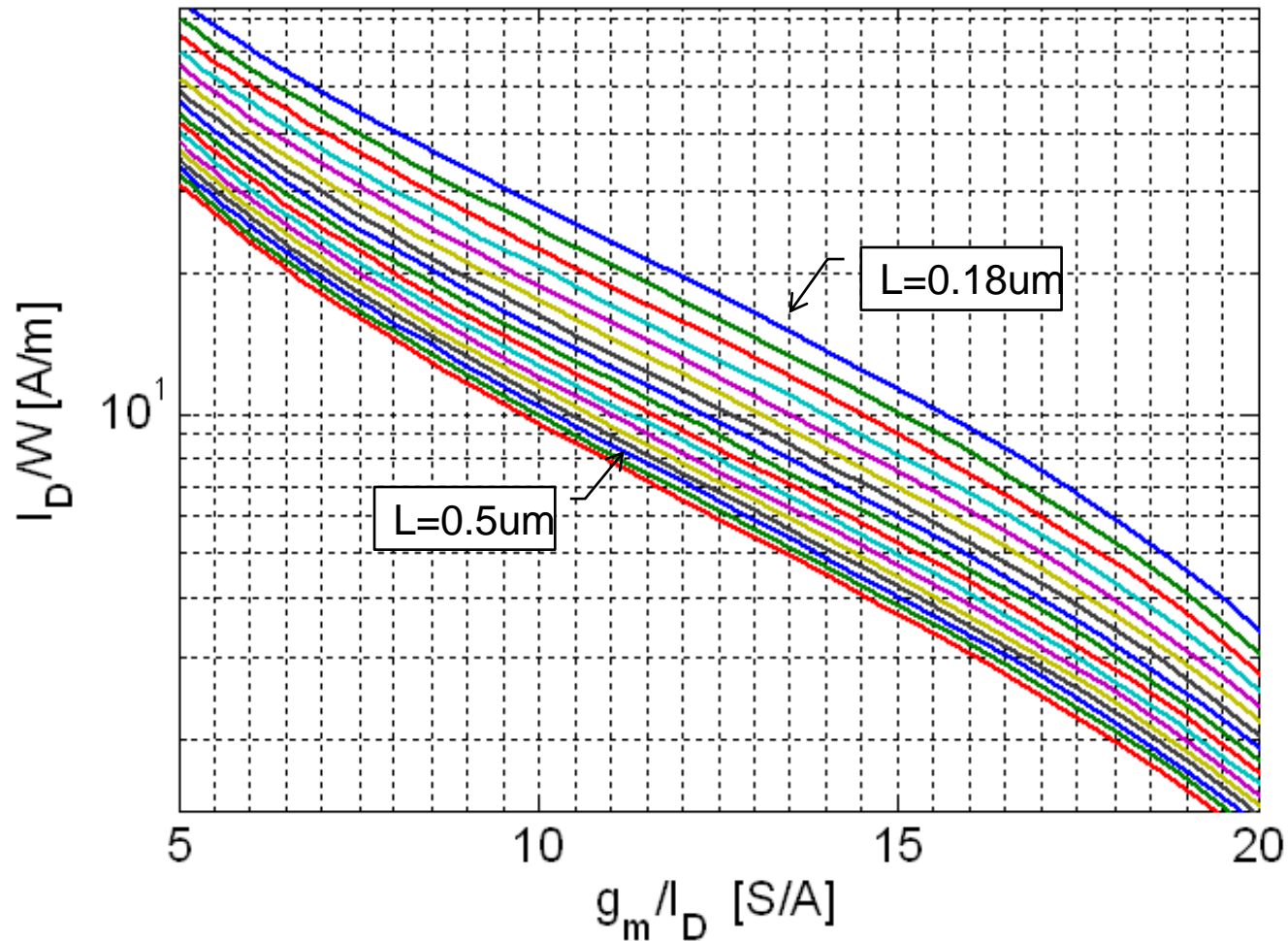


# Intrinsic Gain Chart

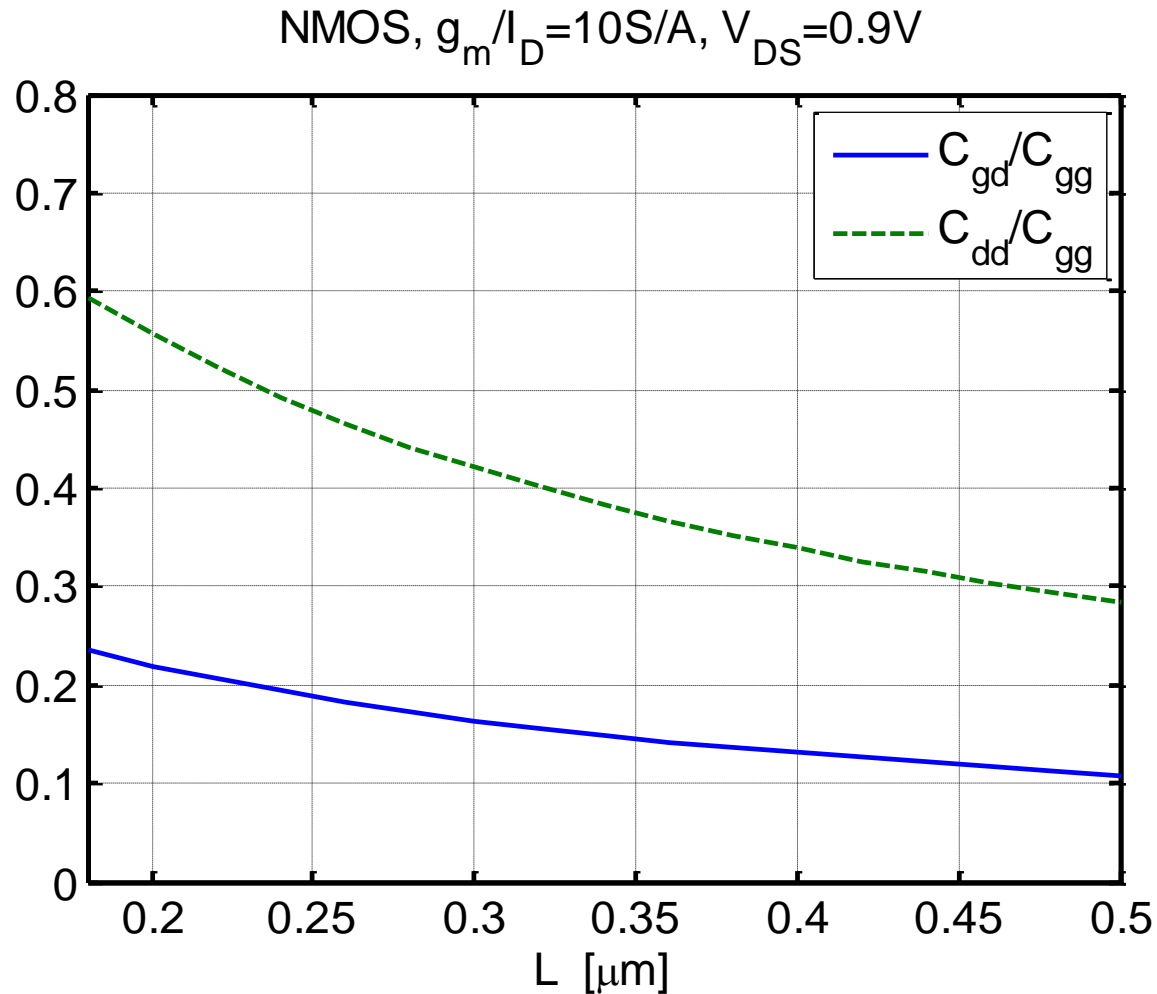


# Current Density Chart

NMOS, 0.18...0.5 $\mu$ m (step=20nm),  $V_{DS}=0.9V$



# Extrinsic Capacitances



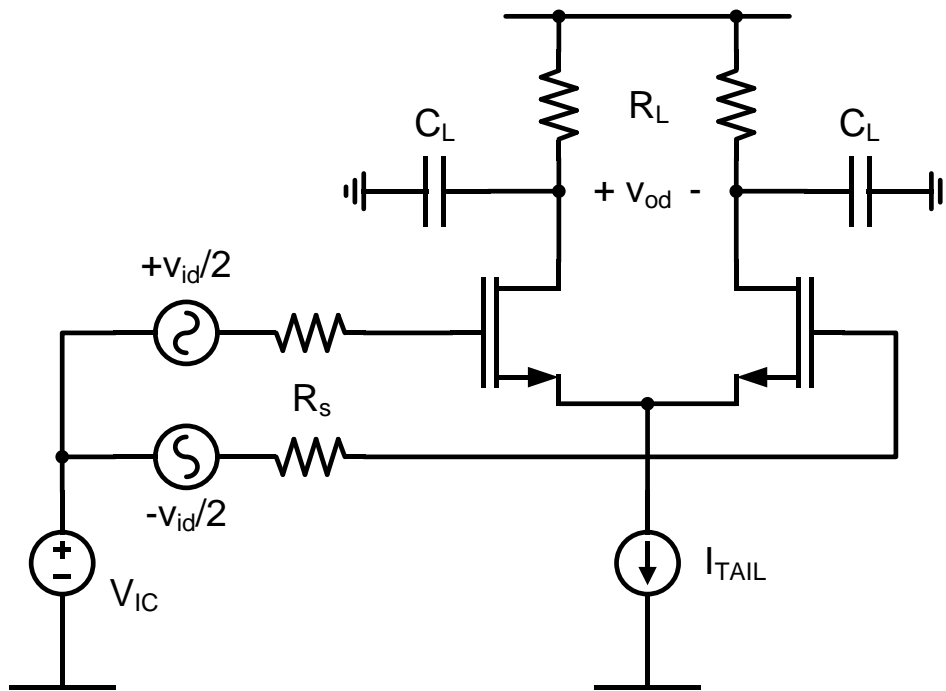
# Generic Design Flow

---

- 1) Determine  $g_m$  (from design objectives)
- 2) Pick  $L$ 
  - Short channel  $\rightarrow$  high  $f_T$  (high speed)
  - Long channel  $\rightarrow$  high intrinsic gain
- 3) Pick  $g_m/I_D$  (or  $f_T$ )
  - Large  $g_m/I_D \rightarrow$  low power, large signal swing (low  $V_{Dsat}$ )
  - Small  $g_m/I_D \rightarrow$  high  $f_T$  (high speed)
- 4) Determine  $I_D$  (from  $g_m$  and  $g_m/I_D$ )
- 5) Determine  $W$  (from  $I_D/W$ )

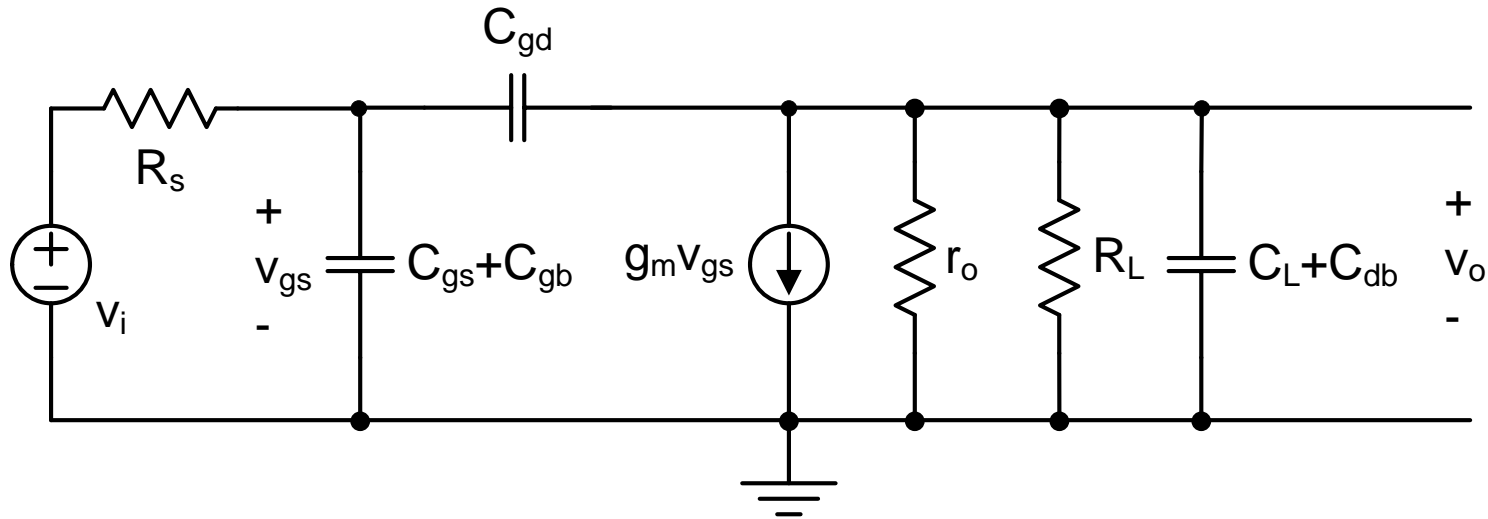
Many other possibilities exist (depending on circuit specifics, design constraints and objectives)

# Back to Our Design Example



- Given specifications and objectives
  - 0.18 $\mu\text{m}$  technology
  - Low frequency gain = -4
  - $R_L=1\text{k}$ ,  $C_L=50\text{fF}$ ,  $R_s=10\text{k}\Omega$
  - Maximize bandwidth while keeping  $I_{TAIL} \leq 600\mu\text{A}$ 
    - Implies  $L=L_{\min}=0.18\mu\text{m}$
  - Determine device width
  - Estimate dominant and non-dominant pole

# Small-Signal Half-Circuit Model



- Calculate  $g_m$  and  $g_m/I_D$

$$|A_{v0}| \cong g_m R_L = 4 \quad \Rightarrow \quad g_m = \frac{4}{1\text{k}\Omega} = 4\text{mS}$$

$$\frac{g_m}{I_D} = \frac{4\text{mS}}{300\mu\text{A}} = 13.3 \frac{\text{S}}{\text{A}}$$

# Zero and Pole Frequencies

---

High frequency zero  
(negligible)

$$\omega_z = \frac{g_m}{C_{gd}} \gg \omega_T$$

Denominator coefficients

$$b_1 = R_s \left[ C_{gs} + C_{gd} (1 + |A_{v0}|) \right] + R_L (C_L + C_{gd})$$
$$b_2 = R_s R_L (C_{gs} C_L + C_{gs} C_{gd} + C_L C_{gd})$$

Dominant pole

$$\omega_{p1} \cong \frac{1}{b_1}$$

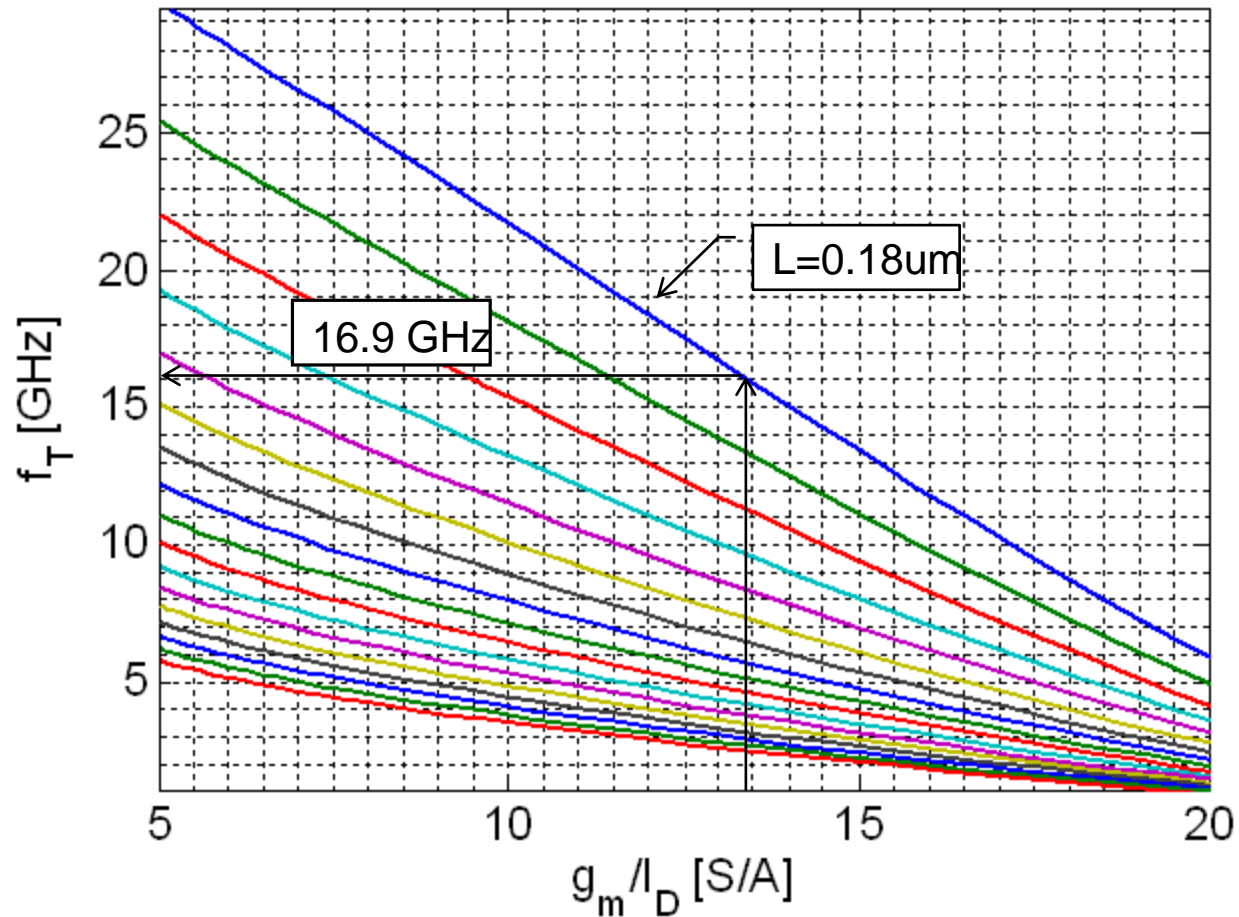
( $C_{db}$  can be added to  $C_L$  if significant))

Nondominant pole

$$\omega_{p2} \cong \frac{b_1}{b_2}$$

# Determine $C_{gg}$ via $f_T$ Look-up

NMOS, 0.18...0.5 $\mu$ m (step=20nm),  $V_{DS}=0.9V$





# Find Capacitances and Plug in

---

$$C_{gg} = \frac{1}{2\pi} \frac{4\text{mS}}{16.9\text{GHz}} = 37.8\text{fF}$$

$$C_{gd} = \frac{C_{gd}}{C_{gg}} C_{gg} = 0.24 \cdot 37.7\text{fF} = 9.0\text{fF}$$

$$C_{dd} = \frac{C_{dd}}{C_{gg}} C_{gg} = 0.60 \cdot 37.7\text{fF} = 22.6\text{fF}$$

$$C_{db} = C_{dd} - C_{gd} = 13.6\text{fF}$$

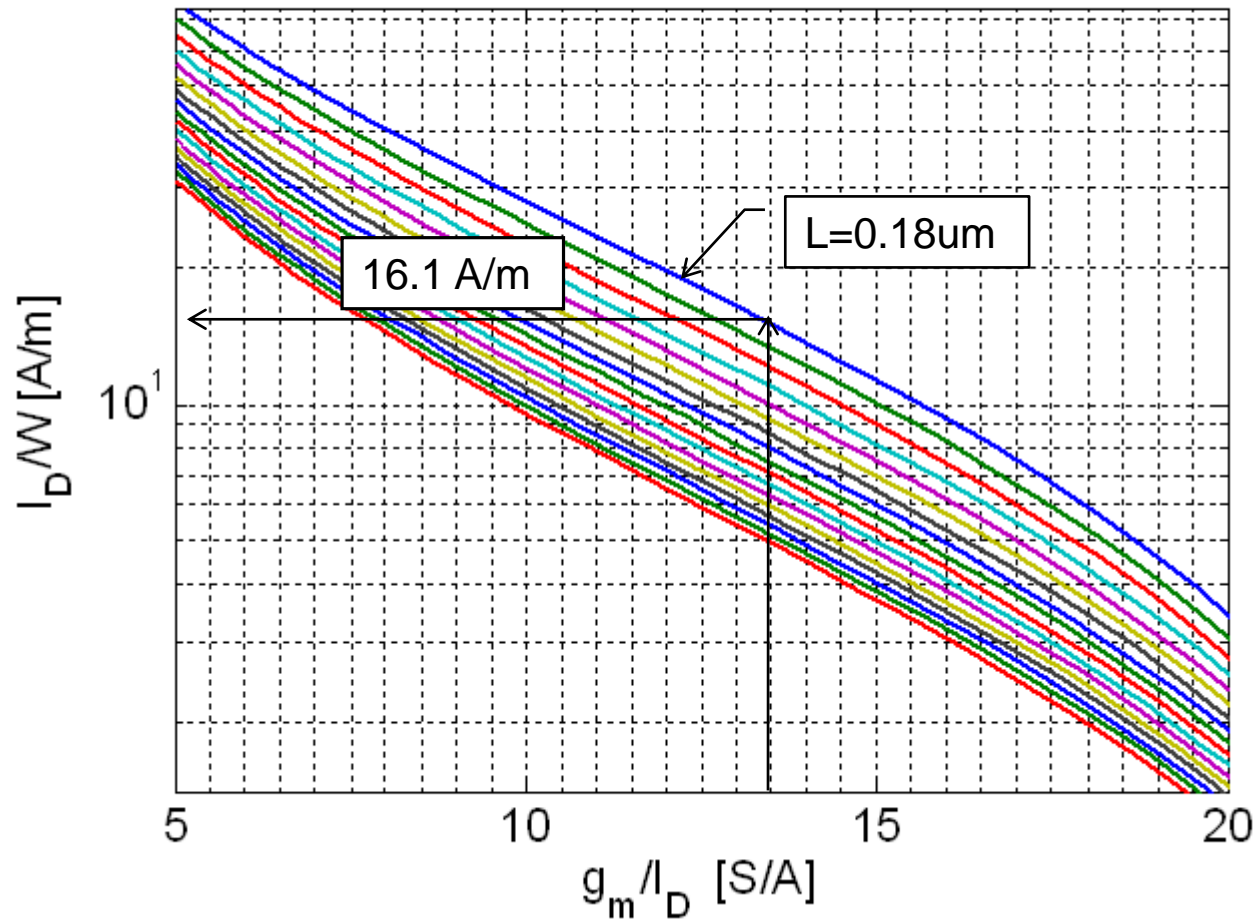
$$C_{gs} = C_{gg} - C_{gd} = 28.8\text{fF}$$

$$f_{p1} \cong 200 \text{ MHz}$$

$$f_{p2} \cong 5.8 \text{ GHz}$$

# Device Sizing

NMOS, 0.18...0.5 $\mu$ m (step=20nm),  $V_{DS}=0.9V$



# Matlab Design Script

---

```
% gm/ID design example
clear all; close all;
load 180n.mat;

% Specs
Av0 = 4; RL = 1e3; CL = 50e-15; Rs = 10e3; ITAIL = 600e-6;

% Component calculations
gm = Av0/RL;
gm_id = gm/(ITAIL/2);
wT = lookup(nch, 'GM_CGG', 'GM_ID', gm_id);
cgd_cgg = lookup(nch, 'CGD_CGG', 'GM_ID', gm_id);
cdd_cgg = lookup(nch, 'CDD_CGG', 'GM_ID', gm_id);
cgg = gm/wT;
cgd = cgd_cgg*cgg;
cdd = cdd_cgg*cgg;
cdb = cdd - cgd;
cgs = cgg - cgd;

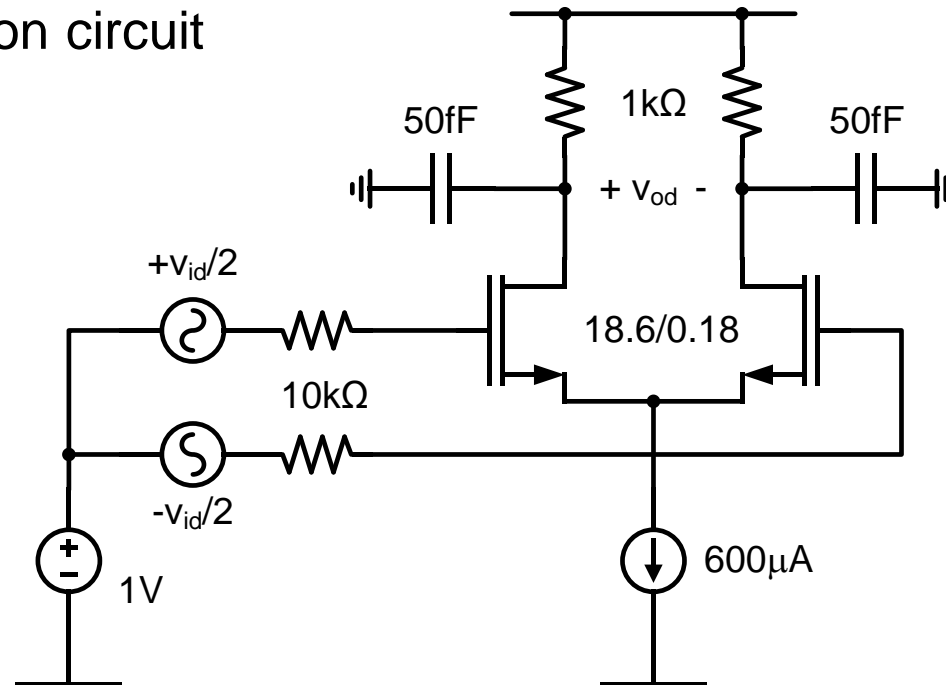
% pole calculations
b1 = Rs*(cgs + cgd*(1+Av0))+RL*(CL+cgd);
b2 = Rs*RL*(cgs*CL + cgs*cgd + CL*cgd);
fp1 = 1/2/pi/b1
fp2 = 1/2/pi*b1/b2

% device sizing
id_w = lookup(nch, 'ID_W', 'GM_ID', gm_id);
w = ITAIL/2 / id_w
```

# Circuit For Spice Verification

- Device width  $W = \frac{I_D}{\frac{I_D}{W}} = \frac{300\mu\text{A}}{16.1\text{A/m}} = 18.6\mu\text{m}$

- Simulation circuit



# Simulated DC Operating Point

| element | 0:m1       | 0:m2       |
|---------|------------|------------|
| model   | 0:nmos214  | 0:nmos214  |
| region  | Saturati   | Saturati   |
| id      | 300.0000u  | 300.0000u  |
| vgs     | 682.4474m  | 682.4474m  |
| vds     | 1.1824     | 1.1824     |
| vbs     | -317.5526m | -317.5526m |
| vth     | 564.5037m  | 564.5037m  |
| vdsat   | 109.0968m  | 109.0968m  |
| vod     | 117.9437m  | 117.9437m  |
| beta    | 37.2597m   | 37.2597m   |
| gam_eff | 583.8490m  | 583.8490m  |
| gm      | 4.0718m    | 4.0718m    |
| gds     | 100.9678u  | 100.9678u  |
| gmb     | 887.2111u  | 887.2111u  |
| cdtot   | 20.8290f   | 20.8290f   |
| cgtot   | 37.4805f   | 37.4805f   |
| cstot   | 42.2382f   | 42.2382f   |
| cbtot   | 31.5173f   | 31.5173f   |
| cgs     | 26.7862f   | 26.7862f   |
| cgd     | 8.9672f    | 8.9672f    |

Good agreement!

Design values

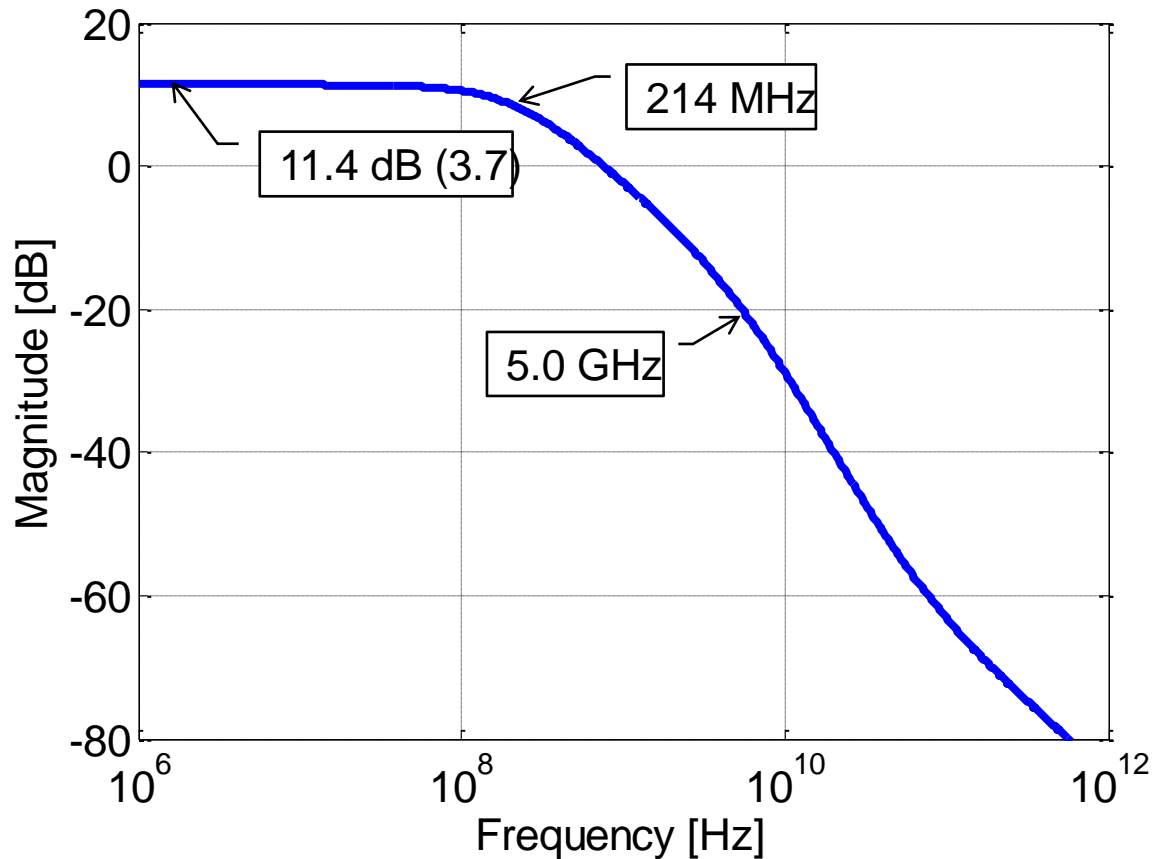
$$g_m = 4 \text{ mS}$$

$$C_{dd} = 22.6 \text{ fF}$$

$$C_{gg} = 37.8 \text{ fF}$$

$$C_{gd} = 9.0 \text{ fF}$$

# Simulated AC Response



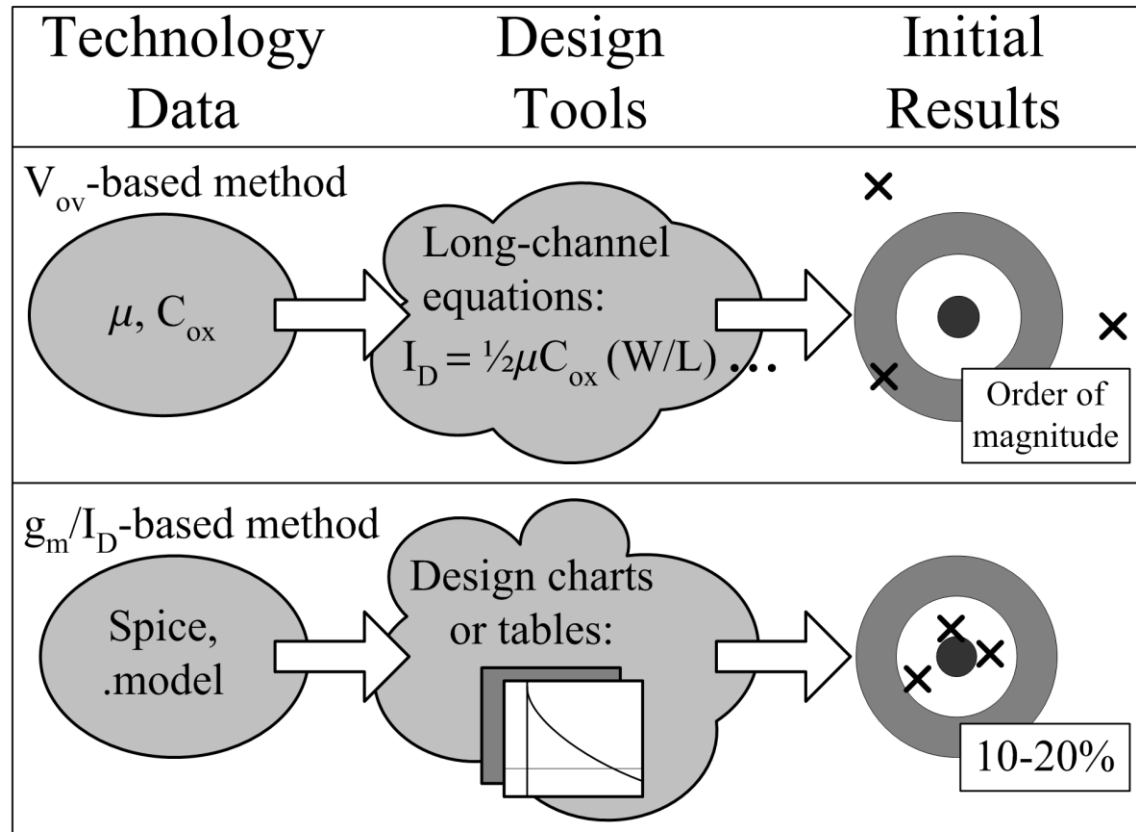
- Calculated values:  $|A_{v0}|=12$  dB (4.0),  $f_{p1} = 200$  MHz,  $f_{p2} = 5.8$  GHz

# Observations

---

- The design is essentially right on target!
  - Typical discrepancies are no more than 10-20%, due to  $V_{DS}$  dependencies, finite output resistance, etc.
- We accomplished this by using pre-computed spice data in the design process
- Even if discrepancies are more significant, there's always the possibility to track down the root causes
  - Hand calculations are based on parameters that also exist in Spice, e.g.  $g_m/I_D$ ,  $f_T$ , etc.
  - Different from square law calculations using  $\mu C_{ox}$ ,  $V_{OV}$ , etc.
    - Based on artificial parameters that do not exist or have no significance in the spice model

# Comparison





# References

---

- F. Silveira et al. "A  $g_m/I_D$  based methodology for the design of CMOS analog circuits and its application to the synthesis of a silicon-on-insulator micropower OTA," IEEE J. Solid-State Circuits, Sep. 1996, pp. 1314-1319.
- D. Foty, M. Bucher, D. Binkley, "Re-interpreting the MOS transistor via the inversion coefficient and the continuum of  $g_m/I_D$ ," Proc. Int. Conf. on Electronics, Circuits and Systems, pp. 1179-1182, Sep. 2002.
- B. E. Boser, "Analog Circuit Design with Submicron Transistors," IEEE SSCS Meeting, Santa Clara Valley, May 19, 2005, <http://www.ewh.ieee.org/r6/scv/ssc/May1905.htm>
- P. Jespers, The  $g_m/I_D$  Methodology, a sizing tool for low-voltage analog CMOS Circuits, Springer, 2010.
- T. Konishi, K. Inazu, J.G. Lee, M. Natsu, S. Masui, and B. Murmann, "Optimization of High-Speed and Low-Power Operational Transconductance Amplifier Using  $g_m/I_D$  Lookup Table Methodology," IEICE Trans. Electronics, Vol. E94-C, No.3, Mar. 2011.

# Summary on $G_m/I_D$ -Based Design

---

- Think  $g_m/I_D$ !
- Weak inversion – moderate inversion – Strong inversion  
     $>20\text{S/A}$     ...     $15\text{ S/A}$     ...     $<10\text{ S/A}$
- $g_m/I_D$  shows up naturally in many circuit calculations and provides a nice link between the most important small signal and large signal parameters
- Once  $g_m/I_D$  has been picked, look up current density and size transistor  $\rightarrow$  Easy
- The hard part is to figure out the best inversion levels to use for the given specs  $\rightarrow$  Clever analysis/scripting is needed...
- When in doubt, start with moderate inversion, often the best of both worlds (compromise between speed and efficiency)